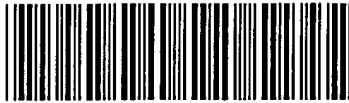


Search Notes

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10/060,301

Examiner

Young J. Kim

Applicant(s)/Patent under
Reexamination

NAKAMURA ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	4/5/2006	YJK